

Search Notes

Application/Control No.

10/644,939

Examiner

Djenane M. Bayard

Applicant(s)/Patent under
Reexamination

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Art Unit

2141

SEARCHED

Class	Subclass	Date	Examiner
709	218	4/16/2007	DB
709	219	4/16/2007	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	4/16/2007	DB